

Silicon Microfabrication Part 1 – Lithography & Etching

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Microfabrication...

1. **Microfabrication** is the process for the production of devices in the submicron to millimeter range.
2. **Micromachining** of silicon and other ceramics is similar to integrated circuit fabrication.
3. **Polymer microfabrication** incorporates thick resist lithography, laser ablation, photopolymerization, thermoplastics and “soft” lithography - microcontact printing (μ CP), PDMS (polydimethylsiloxane) replica molding (REM), microtransfer molding and nanolithography.

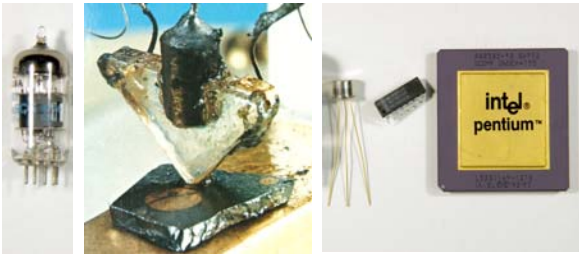
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Micromachining Materials...

- MEMS devices are made from the same materials used for microelectronics, including:
 - Single crystal silicon wafers.
 - Deposited layers of polycrystalline silicon (polysilicon) for resistive elements.
 - Gold, aluminum, copper and titanium for conductors.
 - Silicon oxide for insulation and as a sacrificial layer (for example, to allow release of moving parts, create cantilever, bridge and other 3D structures).
 - Silicon nitride and titanium nitride for electrical insulation and passivation.
- The silicon materials have high strength at small scales which allows higher strain levels and less susceptibility to damage and fracture.

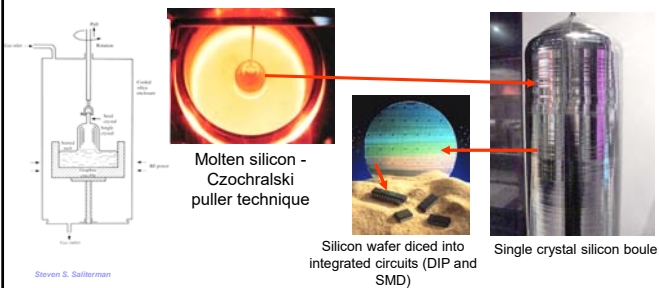
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Microelectronics Revolution



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From Molten Silicon to IC Chips...



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Electronic Grade Silicon (EGS)...

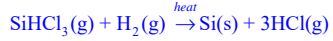
1. Quartzite is placed in a furnace with carbon releasing materials, and reacts as shown, forming metallurgic grade silicon (MGS):



2. MGS is then treated with hydrogen chloride to form trichlorosilane:

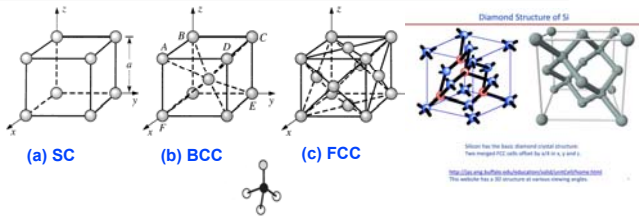


3. Next fractional distillation reduction with hydrogen produces electronic grade silicon (EGS):



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Cubic Crystal System – Unit Cells...

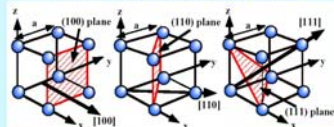


Crystalline silicon forms a covalently bonded structure and coordinates itself tetrahedrally (bottom). Silicon (and germanium) crystallize as two interpenetrating FCC sublattices.

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Image courtesy of Soe, SM.

Silicon Crystal Structure



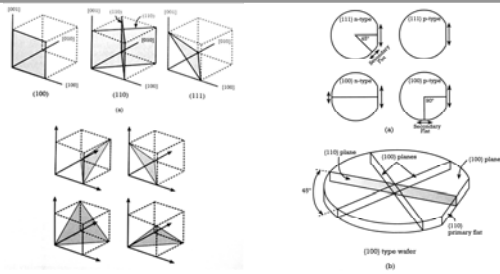
Crystals are characterized by a unit cell which repeats in the x, y, z directions.

- Planes and directions are defined using x, y, z coordinates.
- [111] direction is defined by a vector of 1 unit in x, y and z.
- Planes defined by "Miller indices" – Their normal direction (reciprocals of intercepts of plane with the x, y and z axes).

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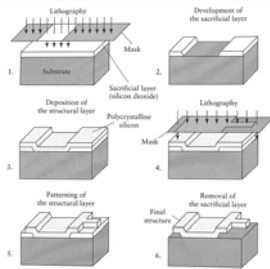
Miller Indices...



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Images courtesy of Madou M.

Basic Surface Micromachining Steps



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Image courtesy of Fatkowi S & Rembold U.

Silicon Wafer Preparation



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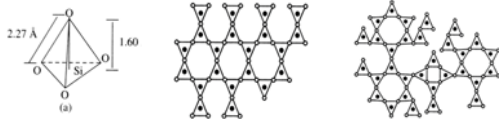
RCA Cleaning Bench...



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Thermal Silicon Oxide...

- SiO_2 is a silicon atom surrounded tetrahedrally by four oxygen atoms.
- Structure may be crystalline (quartz) or amorphous (thermal deposition).



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Images courtesy of Gardner JW.

Thermal Silicon Oxide Methods...

- The chemical reaction that occurs is:

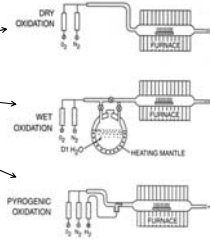


and



- Dry oxidation at 900-1500°C in pure oxygen produces a better oxide, with higher density than steam oxidation.

- Thermal silicon oxide is amorphous.



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Thermal Oxidation Furnace...



Choices of oxygen, steam or inert gas.

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Spin-Casting Resist...



For spinning positive & negative resists, glass, and i.e., PMMA.



Heating plates for soft, hard and dehydration baking.

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Resist Types...

- Both “**positive**” and “**negative**” resists can be chosen, depending on whether it is *desirable to have the opaque regions of the mask protect the resist, and hence the substrate below, vs. having the transparent regions protect the resist when exposed to UV.*
- **Areas where the resist is removed will ultimately be etched. Remember that “positive protects.”**

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- **Positive** resists include poly(methyl methacrylate) (PMMA), and a two-part system, diazoquinone ester plus phenolic novolak resin (DQN).
- **Negative** resists include SU-8, bis(aryl)azide rubber and Kodak KTFR.
- **Critical Dimension** - this is the smallest feature size to be produced.
- **Resolution** – smallest line width to be consistently patterned.

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Mask Fabrication



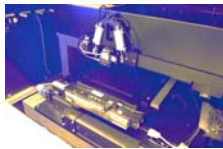
The Heidelberg



Nanolium
 2401 Technology Blvd
 Westlake Village, CA 91361
 www.nanolium.com

Client	LINCOLN	SP MINNESOTA	2.0
Part #	8000-000-01-LR2-100-1010-00	Optical Density	2.0
P.O.	ENERGY CARE	Material	475
Production Lot Number	8000	Photo Resist Thickness	8000-A
Glass Type	Blank Glass	Photo Resist Type	AF 1010
Mask Code	021118	Photo Resist Lot	28-100
		Photo Resist Batch Temp	100.0

Unexposed Masks
(Resist is Pre-applied)



Mask Carriage

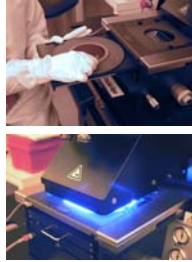
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Contact Alignment...



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UV Exposure at 350-500 nm...



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Cannon Stepper (Alternative to Contact Aligner)...



Projection system. Resolution down to .5 micron, compared to about 3 microns for the contact aligner.

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Developing the UV Exposed Wafer...



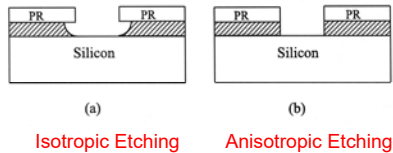
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Etching Methods

- **Subtractive** processes:
 - **Dry etching** (plasma),
 - **Glow discharge** methods (diode setups):
 - **Plasma etching (PE)**,
 - **Reactive ion etching (RIE)**,
 - **Physical sputtering (PS)**.
 - **Ion beam** methods (triode setups):
 - **Ion beam milling (IBM)**,
 - **Reactive ion beam etching (RIBE)**,
 - **Chemical assisted ion beam etching (CAIBE)**.
 - **Deep Reactive Ion Etching (DRIE)**.
 - **Wet etching** (chemical liquids).

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Etching Profiles...



Isotropic Etching

Anisotropic Etching

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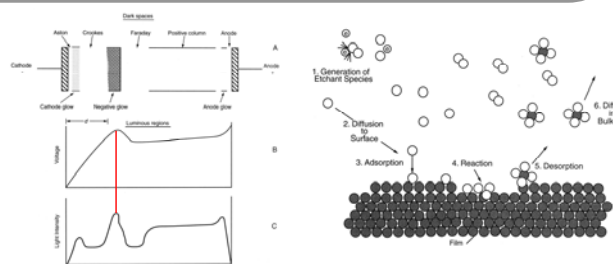
Image courtesy of Zale B.

Energy, Vacuum & Directionality...

- **Plasma Etching** occurs at relatively lower energy and higher pressure (less vacuum), and is isotropic, selective and less prone to cause damage.
- **Reactive Ion Etching** is more middle ground in terms of energy and pressure, with better directionality.
- **Physical Sputtering** and **Ion Beam Milling** rely on physical momentum transfer from higher excitation energies and very low pressures, and result in poor selectivity with anisotropic etching and increased radiation damage.

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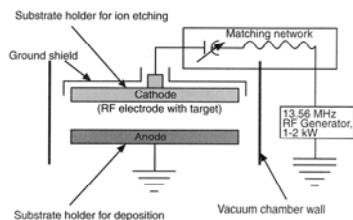
Plasma Etching (PE)...



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Images courtesy of Madou M.

Reactive Ion Etching (RIE)...



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Image courtesy of Madou M.

Reactive Ion Etcher...



The system is designed to etch silicon, silicon nitride, silicon oxide, photoresists, other allowed organics and semiconductor materials.

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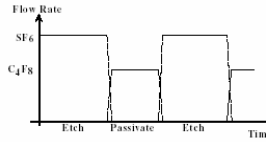
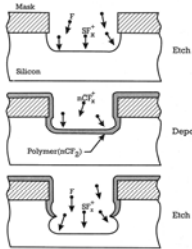
Gases for the RIE...



Etchant gases available:
Argon (Ar),
Trifluoromethane (CHF₃)
Tetrafluoromethane (CF₄)
Oxygen (O₂)
Sulphur Hexafluoride (SF₆)
Methanol (CH₃OH)

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Deep Reactive Ion Etching (DRIE)



Sulfur hexafluoride (SF₆) is flowed during the etching cycle then Octafluorocyclobutane (C₄F₈) during the sidewall protection cycle.

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Left: Madoui M. Fundamentals of Microfabrication: The Science of Miniaturization, 2nd ed. CRC Press, Boca Raton, FL (2002). Right: Reis, A. & R. Bhattacharya. Deep Reactive Ion Etching (DRIE). ENEC416, 3/10/2004.

Deep Reactive Ion Etcher...



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Physical Sputtering

- Bombarding a surface with inert ions (e.g., argon) has an effect related to the kinetic energy of the incoming particles.
- At energies < 3 eV (electron volts) particles are simply reflected or absorbed.
- At surface energies between 4-10 eV some surface sputtering occurs.
- At surface energies of 10-5000 eV momentum transfer causes bond breakage and ballistic material ejection across the reactor to the collecting surface. A low pressure and long mean free path are necessary to prevent the material from redepositing.
- Implantation (doping) occurs at 10,000-20,000 eV.

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Sputter Yield...

- **Sputter yield** is the number of atoms removed from the surface per incident ion.
- **Sputter yield depends on the following:**
 - Incident ion energy (max yield 5-50 keV).
 - Mass of the ion
 - Mass of the substrate atom to be etched away.
 - Crystallinity and crystal orientation of the substrate.
 - Temperature of the substrate
 - Partial pressure of oxygen in the residual gas.

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Ion Beam Milling (IBM)...

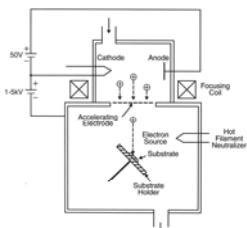
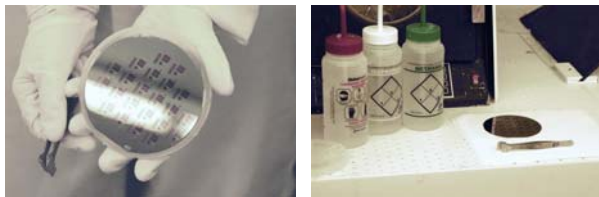


Image courtesy of Madou M.

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Resist Stripping...



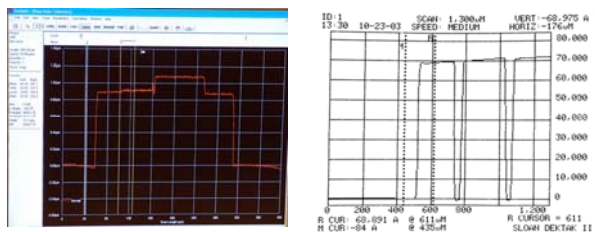
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Profilometry...



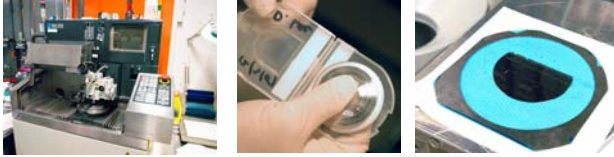
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Profilometer Screen Display...

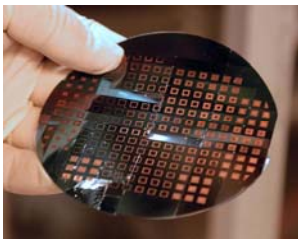


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Wafer Cutting - Dicing Chips...

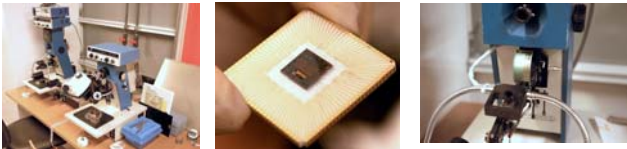


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Wire Bonding...



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Summary

- **Microfabrication** is the process for the production of devices in the submicron to millimeter range.
- **Micromachining of silicon and other ceramics is similar to integrated circuit fabrication.**
- **Crystalline silicon** forms a covalently bonded structure and coordinates itself **tetrahedrally** (bottom). Silicon (and germanium) crystalize as two interpenetrating **FCC** sub lattices.

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- **Surface micromachining concepts discussed:**
 - Mask creation,
 - Silicon wafer preparation,
 - Thin-films deposition such as SiO_2 ,
 - Resist (positive or negative) application,
 - UV exposure and development,
 - Etching methods (subtractive processes),
 - Resist stripping,
 - Inspection with profilometer.
- **Dicing and Wire Bonding**

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